

| | | | | |
|-----------------------------------|--|----------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination HEIKKILA ET AL. | |
| | | Examiner José A Fortuna | Art Unit 1731 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|-----------------|----------------|
| A | US-2001/0028955 | 10-2001 | Luo et al. | 428/393 |
| B | US-6,605,350 | 08-2003 | Sealey et al. | 428/393 |
| C | US-6,528,163 | 03-2003 | Sealey et al. | 428/393 |
| D | US-6,471,727 | 10-2002 | Luo et al. | 8/116.1 |
| E | US-6,444,314 | 09-2002 | Luo et al. | 428/393 |
| F | US-6,440,547 | 08-2002 | Luo et al. | 428/292.7 |
| G | US-2002/0195213 | 12-2002 | Izumi et al. | 162/55 |
| H | US-2003/0037892 | 02-2003 | Heikkila et al. | 162/17 |
| I | US- | | | |
| J | US- | | | |
| K | US- | | | |
| L | US- | | | |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
| Q | | | | | |
| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| | |
|---|---|
| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| U | |
| V | |
| W | |
| X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.